# 27HC128 O.T.P. One Time Programmable 128K (16K $\times$ 8) EPROMs

Preliminary Specification

#### **Application Specific Products**

#### DESCRIPTION

The 27HC128 CMOS, O.T.P. EPROM is a high-speed electrically programmable Read Only Memory. It is organized as 16,384 words of 8 bits and operates from a single 5V  $\pm$  10% power supply. All outputs offer 3-State operation and are fully TTL compatible.

The 27HC128 uses advanced CMOS circuitry which allows operation at bipolar PROM speeds while consuming lower power. The highest degree of protection against latch-up is achieved through epitaxial processing simplifying the design of electronic equipment which is subject to high noise environments.

The 27HC128 is available in industry standard packages with the same pinout as most 128K bipolar PROMs. This makes it easy to upgrade systems currently using bipolar PROMs and provide a lower power memory system solution.

#### **FEATURES**

- Address access time:
  - 27HC128-55 55ns max
  - 27HC128-45 45ns max
- Operating I<sub>CC</sub>: 110mA max
- 3-State outputs
- JEDEC standard 28-pin DIP and 28-pin PLCC package
- Direct replacement for standard 128K TTL PROMs
- Fully TTL compatible

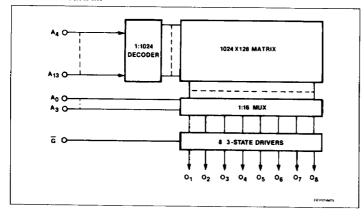
#### APPLICATIONS

- Prototyping and volume production
- High-performance mini- and microcomputers
- High-speed program store and look-up tables

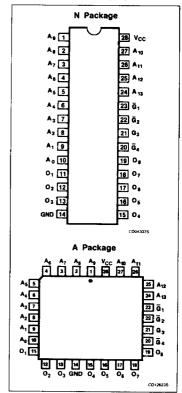
#### ORDERING INFORMATION

DESCRIPTION	ORDER CODE				
DESCRIPTION	45ns	55ns			
28-pin plastic DIP (600mil-wide)	27HC128-45 N	27HC128-55 N			
28-pin plastic leaded chip carrier	27HC128-45 A	27HC128-55 A			

#### **BLOCK DIAGRAM**



# PIN CONFIGURATIONS



### PIN NAMES

	•	
A <sub>0</sub> - A <sub>13</sub>	Address inputs	
O <sub>1</sub> - O <sub>8</sub>	Data outputs	
G-G	Output Enables	
Vcc	Supply voltage	
GND	Ground (V <sub>SS</sub> )	

# One Time Programmable 128K (16K imes 8) EPROMs

27HC128 O.T.P.

# ABSOLUTE MAXIMUM RATINGS<sup>1</sup>

SYMBOL PARAMETER		RATING	UNIT	
V <sub>I</sub> , V <sub>O</sub>	Voltage on any pin <sup>2</sup>	-0.5 to V <sub>CC</sub> + 1V	٧	
TA	Temperature under bias	-10 to +85	°C	
T <sub>STG</sub>	Storage temperature range	-65 to +150	°C	
V <sub>PP</sub> Voltage on G pin		-0.5 to 13.5	٧	

#### DC OPERATING CONDITIONS 0°C < TA < +70°C

SYMBOL PA		ARAMETER TEST CONDITIONS	LIMITS			
	PARAMETER		Min	Тур	Max	UNIT
Supply vol	tage					
V <sub>CC</sub>		GND = 0V	4.5	5.0	5.5	٧
Input volta	ige					
V <sub>IH</sub>	High		2.0		V <sub>CC</sub> + 0.5	٧
V <sub>IL</sub>	Low		-0.1		0.8	V

## DC ELECTRICAL CHARACTERISTICS 0°C $\leq$ T<sub>A</sub> $\leq$ +70°C, 4.5V $\leq$ V<sub>CC</sub> $\leq$ 5.5V

			LIMITS			
SYMBOL	PARAMETER	TEST CONDITIONS	Min	Тур	Max	UNI
Input Curre	nt					
I <sub>IH</sub>	High	V <sub>IN</sub> = V <sub>CC</sub>			10	μΑ
I <sub>IL</sub> 3	Low	V <sub>IN</sub> = 0.45V			10	μΑ
Output Curi	rent					
lo	Leakage	V <sub>OUT</sub> = 0 to V <sub>CC</sub>			± 10	μΑ
los	Output short-circuit current <sup>4</sup>	$V_{OUT} = 0V, \overline{G} = V_{IL}$	-15		-70	m/
Supply Curi	rent					
Icc	V <sub>CC</sub> operating current	G = V <sub>IH</sub> , O <sub>1 - 8</sub> = 0mA, f = 20MHz		110	m/	
Input Voltag	ge					
V <sub>IC</sub>	Input clamp voltage	I <sub>IC</sub> = -12mA			-1.2	V
Output Voit	age					
V <sub>OH</sub>	High	I <sub>OH</sub> = -4mA	2.4			V
V <sub>OL</sub>	Low	I <sub>OL</sub> = 16mA			0.45	٧
Capacitance	e <sup>5</sup>					
		f = 1MHz, T <sub>A</sub> = 25°C				
		$V_{CC} = 5.0V$				
C <sub>IN</sub>	Input	V¹N = 0∨		ļ	6	pf
Cout	Output	V <sub>OUT</sub> = 5.0V			12	₽F

#### NOTES:

224 February 1989

<sup>1.</sup> Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only. Functional operation of this device at these or any other conditions above those indicated in the operational sections of this specification is not implied and exposure to absolute maximum rating conditions for extended periods may affect device reliability.

2. Minimum DC input voltage is -0.5V. During transitions the inputs may undershoot to -2.0V for periods less than 20ns.

<sup>3.</sup> Input current for  $\overline{G}$  input only = -100 $\mu$ A

<sup>4.</sup> Test one output at a time for 1 sec max

<sup>5.</sup> Capacitance limits are sampled and not 100% tested

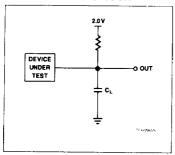
# One Time Programmable 128K (16K imes 8) EPROMs

# 27HC128 O.T.P.

# AC ELECTRICAL CHARACTERISTICS $C_L$ = 30pF, $R_1$ = 98 $\Omega_{\rm c}$ 0°C $\!\!\!<$ $\!\!\!<$ $\!\!\!<$ $\!\!\!+$ 70°C, 4.5V $\!\!\!<$ $\!\!\!<$ $\!\!\!\!<$ $\!\!\!<$ $\!\!\!<$ 5.5V

SYMBOL	PARAMETER	то	FROM	27HC128-45		27HC128-55		
		,0		Min	Max	Min	Max	UNIT
t <sub>AA</sub>	Address access time	Output	Address		45		55	ns
t <sub>ES</sub>	Output Enable access time	Output	Output Enable		25		30	ns
t <sub>EO</sub>	Output disable time	Output	Output Enable		25		30	ns

## AC TEST LOAD CIRCUIT



# **VOLTAGE WAVEFORMS**

